

Notice of References Cited	Application/Control No. 10/002,978	Applicant(s)/Patent Under Reexamination HSIEH ET AL.
	Examiner Thao X Le	Art Unit 2814

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	B	US-6,187,633	02-2001	Dong et al.	438/261
	C	US-4,954,867	09-1990	Hosaka, Takashi	257/639
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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